



ILV

Institut Lavoisier de Versailles

M. MATHIEU FRÉGNAUX

INGENIEUR(E) DE RECHERCHE

IR - Equipe EPI - Assistant de Prévention

Université de Versailles Saint-Quentin-en-Yvelines > UFR des sciences > Institut Lavoisier de Versailles (ILV) >

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Coordonnées

Adresse

45 avenue des États-Unis Bâtiment Lavoisier 78035 Versailles Cedex

BUREAU

CEFS2

TÉL

01 39 25 43 95

ADRESSE MAIL

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A

Itinéraire vers ce lieu **Site de l'UFR des Sciences** 45 avenue des États-Unis
78035 Versailles cedex

Discipline(s)

Chimie, Physique

Thèmes de recherche

Research topics: surface and material science

Topic I: Photoemission and related techniques

- » ILV scientific and technical manager in photoemission
- » XPS, UPS characterizations (regular and angle resolved analyses, mapping, depth profiling)
- » Operando XPS (device polarization, optical stimuli)
- » REELS, LEIS, in situ annealing
- » Synchrotron based photoemission: NAP-XPS and time resolved PES (TEMPO /SOLEIL), PEEM (HERMES/SOLEIL), HAXPES (KMC-1/BESSY), XAS (APE /ELETTRA)

Topic II: Optical characterizations

- » Laser safety manager
- » ILV-EPI scientific and technical manager of optical characterization tools
- » Photoluminescence and Raman spectrometry on thin films and solutions
- » Spectroscopic ellipsometry

Field of expertise

- » Semiconductors (II-VI, III-V, IV)
- » Oxides (perovskite oxides)
- » 2D materials

R&D projects with industrial partners

- » III-V Lab, Thales Research & Technology, 3SP Technologies, Lynred, Linxens
- » TotalEnergies, Hutchinson
- » Saint Gobain Recherche
- » IPVF
- » Valeo

Activités / CV

Current Position

- » **Since 2015. Research Engineer** at CNRS (French National Centre for Scientific Research
Co-manager of CEFS2 facilities, responsible of optical benches (PL, Raman, ellipsometry)
Equipe EPI, Institut Lavoisier de Versailles, France

Education

- » **2012 PhD in Condensed Matter Physics** obtained at University of Lorraine, Metz (France)
Thesis: Elaboration and characterization of cadmium sulfide (CdS) nanocrystals – nanostructured thin film deposition
Supervision: Jean-Pierre Laurenti / Jean-Jacques Gaumet

Previous positions

- » **2014-2015: Research Scientist (Postdoctoral Fellow)**
French Alternative Energies and Atomic Energy Commission (CEA) - LETI / PFNC - Grenoble (France)
Advanced characterization protocol development for bidimensional (2D) transition metal dichalcogenide monolayers (MoS₂) - integration in microelectronic devices (transistors)
- » **2013-2014: Research associate – lecturer (ATER)**
Université de Strasbourg (France)
Teaching Physics at Télécom Physique Strasbourg
Study of doped silicon (Si), germanium (Ge) and ternary In_xGa_{1-x}As nanocrystals grown by ion beam synthesis: potential active layers for solar cells or memories
- » **2013: Postdoctoral Fellow**
CNRS / Ecole Nationale Supérieure des Industries Chimiques (ENSIC) - Nancy

(France)

ANR «NanoZnOTox»: Bioperception, toxicity and stability of zinc oxide (ZO) nanocrystals.

Informations complémentaires

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